

METHOD AND APPARATUS OF DETERMINING DEFECT-FREE
SEMICONDUCTOR INTEGRATED CIRCUIT

ABSTRACT OF THE DISCLOSURE

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10 A method and apparatus of determining a defect-free
semiconductor integrated circuit such as CMOS IC able to
determine a defect-free device regardless of the
existence of a circuit leakage current, including a step
of selecting defect-free CMOS integrated circuit from a
group of CMOS integrated circuits a step of successively
inspecting the test IC and reference defect-free IC for
resemblance of features of quiescent power supply
15 currents (QPSCs), and a step of determining if there is
resemblance between the features test IC is defect-free.

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